



SiTest Solutions Ltd.

Silicon Test Solutions, Services, & Strategies



ISO 9001:2000

July 2008 Newsletter

Test & Product Engineering Services from Design to Production

Verigy V5000 Tester SiTest Solutions has installed a new Verigy V5000e Test system in its Hong Kong facility. We now offer full service NAND Flash and specialty memory testing. The tester was most recently used to develop a test solution for a 16Gb /32Gb Solid State Drive (SSD) device. The SSD device is an integrated NAND Flash memory with an embedded controller in a BGA package. This Package-In-Package Solution is a direct replacement for a hard disk drive.



Intelligent Burn-In System has been installed in the Hong Kong facility. The proprietary design features 8-board capacity, temperature range up to +200C, and the ability to test and capture real time failures during dynamic operation. Applications for Memory, RF devices, Power Management Units, Power MOSFETs, and High-speed ASICs have already been implemented.



RF Test Capabilities Panda Chip of Hong Kong has selected SiTest Solutions to develop its RF test strategies and solutions for their RF Power Amplifier family of devices and RF modules. SiTest Solutions will use the LTX X-series RF tester for both the characterization and volume Production testing of the RF devices. www.pandachip.com

Expanded Engineering Team We have expanded our engineering team and expertise in Hong Kong, and now have support in both Manila (Philippines) and Shanghai (China).

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